## - 5- $\Omega$ Switch Connection Between Two Ports <br> - TTL-Compatible Input and Output Levels <br> - Designed to Be Used in Level-Shifting Applications <br> - Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), Quarter-Size Small-Outline (DBQ), and Thin Shrink Small-Outline (PW) Packages, Ceramic Flat (W) Package, Ceramic DIPs (JT), and Ceramic Chip Carriers (FK) <br> description

The 'CBTD3384 provide ten bits of high-speed TTL-compatible bus switching. The low on-state resistance of the switches allows connections to be made without adding propagation delay. A diode to $\mathrm{V}_{\mathrm{CC}}$ is integrated on the die to allow for level shifting between $5-\mathrm{V}$ inputs and $3.3-\mathrm{V}$ outputs.

These devices are organized as two 5-bit switches with separate output-enable ( $\overline{\mathrm{OE} \text { ) }}$ inputs. When $\overline{O E}$ is low, the switch is on and port A is connected to port B . When $\overline{\mathrm{OE}}$ is high, the switch is open and a high-impedance state exists between the two ports.
The SN54CBTD3384 is characterized for operation over the full military temperature range from $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$. The SN74CBTD3384 is characterized for operation from $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$.

SN54CBTD3384... JT OR W PACKAGE
SN74CBTD3384... DB, DBQ, DW, OR PW PACKAGE
(TOP VIEW)


SN54CBTD3384... FK PACKAGE (TOP VIEW)


NC - No internal connection

FUNCTION TABLE

| $\mathbf{1} \overline{\mathrm{OE}}$ | 2 $\overline{\mathrm{OE}}$ | 1B1-1B5 | 2B1-2B5 |
| :---: | :---: | :---: | :---: |
| L | L | 1A1-1A5 | 2A1-2A5 |
| L | $H$ | $1 A 1-1 A 5$ | $Z$ |
| $H$ | $L$ | $Z$ | $2 A 1-2 A 5$ |
| $H$ | $H$ | $Z$ | $Z$ |

## logic diagram



Pin numbers shown are for the DB, DBQ, DW, JT, PW, and W packages.

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted) $\dagger$


recommended operating conditions

|  |  | SN54CBTD3384 |  | SN74CBTD3384 |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | MIN | MAX | MIN | MAX |  |
| $\mathrm{V}_{\mathrm{CC}}$ | Supply voltage | 4.5 | 5.5 | 4.5 | 5.5 | V |
| $\mathrm{V}_{\mathrm{IH}}$ | High-level control input voltage | 2 |  | 2 |  | V |
| $\mathrm{V}_{\text {IL }}$ | Low-level control input voltage |  | 0.8 |  | 0.8 | V |
| $\mathrm{T}_{\text {A }}$ | Operating free-air temperature | -55 | 125 | -40 | 85 | ${ }^{\circ} \mathrm{C}$ |

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| PARAMETER |  | TEST CONDITIONS |  |  | SN54CBTD3384 |  |  | SN74CBTD3384 |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | MIN | TYP $\dagger$ | MAX | MIN | TYP $\dagger$ | MAX |  |
| $\mathrm{V}_{\mathrm{IK}}$ |  |  |  |  | $\mathrm{V}_{\mathrm{CC}}=4.5 \mathrm{~V}$, | $\mathrm{I}=-18 \mathrm{~mA}$ |  |  |  | -1.2 |  |  | -1.2 | V |
| $\mathrm{V}_{\mathrm{OH}}$ |  | See Figure 1 |  |  |  |  |  |  |  |  |  |
| I |  | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$, | $\mathrm{V}_{1}=5.5 \mathrm{~V}$ | GND |  |  | $\pm 1$ |  |  | $\pm 1$ | $\mu \mathrm{A}$ |
| ICC |  | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$, | l | $\mathrm{V}_{\mathrm{I}}=\mathrm{V}_{\text {CC }}$ or GND |  |  | 1.5 |  |  | 1.5 | mA |
| ${ }^{1} \mathrm{CC}^{\ddagger}$ | Control pins | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$, One input at 3.4 V , Other inputs at $\mathrm{V}_{\mathrm{CC}}$ or GND |  |  |  |  | 2.5 |  |  | 2.5 | mA |
| $\mathrm{C}_{\mathrm{i}}$ | Control pins | $\mathrm{V}_{\mathrm{l}}=3 \mathrm{~V}$ or 0 |  |  |  | 3 |  |  | 3 |  | pF |
| $\mathrm{C}_{\mathrm{io} \text { (OFF) }}$ |  | $\mathrm{V}_{\mathrm{O}}=3 \mathrm{~V}$ or 0 , | $\overline{\mathrm{OE}}=\mathrm{V}_{\mathrm{C}}$ |  |  | 3.5 |  |  | 3.5 |  | pF |
| $\mathrm{r}_{\mathrm{on}}$ § |  | $\mathrm{V}_{\mathrm{CC}}=4.5 \mathrm{~V}$ | $\mathrm{V}_{\mathrm{I}}=0$, | I $=64 \mathrm{~mA}$ |  | 5 |  |  | 5 | 7 | $\Omega$ |
|  |  | $\mathrm{V}_{\mathrm{I}}=0$, | I $=30 \mathrm{~mA}$ |  | 5 |  |  | 5 | 7 |  |
|  |  | $\mathrm{V}_{1}=2.4 \mathrm{~V}$ | $\mathrm{I}=15 \mathrm{~mA}$ |  | 35 |  |  | 35 | 50 |  |

$\dagger$ Typical values are at $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$.
$\ddagger$ This is the increase in supply current for each input that is at the specified TTL voltage level rather than $V_{C C}$ or GND.
§ Measured by the voltage drop between the $A$ and $B$ terminals at the indicated current through the switch. On-state resistance is determined by the lowest voltage of the two ( $A$ or $B$ ) terminals.
switching characteristics over recommended ranges of supply voltage and operating free-air temperature range, $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}$ (unless otherwise noted) (see Figure 2)

| PARAMETER | FROM (INPUT) | $\begin{gathered} \text { TO } \\ \text { (OUTPUT) } \end{gathered}$ | SN54CBTD3384 |  | SN74CBTD3384 |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | MAX | MIN | MAX |  |
| $t_{\text {pd }}{ }^{\text {I }}$ | A or B | B or A |  | 0.25 |  | 0.25 | ns |
| ten | $\overline{\mathrm{OE}}$ | A or B | 2.2 | 9.7 | 2.3 | 7 | ns |
| $\mathrm{t}_{\text {dis }}$ | $\overline{\mathrm{OE}}$ | A or B | 1.5 | 8.6 | 1.7 | 5.3 | ns |

T This parameter is warranted but not production tested. The propagation delay is based on the RC time constant of the typical on-state resistance of the switch and a load capacitance of 50 pF , when driven by an ideal voltage source (zero output impedance).


OUTPUT VOLTAGE HIGH
vs
SUPPLY VOLTAGE


Figure 1. $\mathrm{V}_{\mathrm{OH}}$ Values

## PARAMETER MEASUREMENT INFORMATION



Figure 2. Load Circuit and Voltage Waveforms

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